Group Testing:

Something old, Something new, Something borrowed

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 - Negative test: all in the pool are uninfected
 - Positive test: at least one soldier is infected



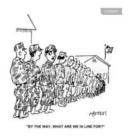
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- First studied by Robert Dorfman in US in the 1940s for syphilis testing amongst soldiers.
- Can do individual testing, inefficient since most tests will be negative.
- Key idea: 'pool' samples from many soldiers and test it
 - Negative test: all in the pool are uninfected
 - Positive test: at least one soldier is infected
- Goal: design pooling strategies to minimize number of tests.

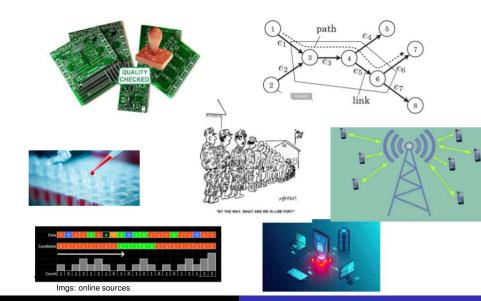


"BY THE WAY, WHAT ARE WE IN LINE FOR?"

Group testing: applications



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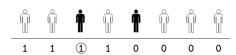


Model



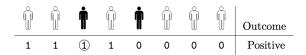
- n items V, unknown subset K of defectives with size at most k.
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 - ▶ k ≪ n
- Each test t can be represented by $\mathbf{x} \in \{0,1\}^n$.
 - $\mathbf{x}_{i}^{t} = 1$ if item *i* included in test.

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 - \triangleright $k \ll n$
- Each test t can be represented by $\mathbf{x} \in \{0,1\}^n$.
 - $\mathbf{x}_{i}^{t} = 1$ if item *i* included in test.
- Outcome $y_t = \bigvee_{i \in \mathcal{K}} \mathbf{x}_i^t$.

$\hat{\Box}$		å		å	Ô	$\hat{\Box}$		
W	W	T	W	T	W	W	W	Outcome
1	1	1	1	0	0	0	0	Positive
0	0	0	0	1	1	1	1	Positive
1	1	0	0	0	0	0	0	Negative
0	0	1	0	0	0	0	0	Positive
0	0	1	0	1	1	0	0	Positive
0	0	0	0	1	0	0	0	Positive

• Test design
$$\mathbf{X} \in \{0, 1\}^{T \times n}$$
, output $\mathbf{y} = \bigvee_{i \in \mathcal{K}} \mathbf{X}_i$.

?	?	?	?	?	?	?	?	y
1	1	1 0 0 1 1	1	0	0	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

- Testing design $\mathbf{X} \in \{0, 1\}^{T \times n}$, output $\mathbf{y} = \bigvee_{i \in \mathcal{K}} \mathbf{X}_i$.
- **X** is *feasible* if we can recover any $\mathcal K$ from $\mathbf y, |\mathcal K| \le k$.

?	?	?	?	?	?	?	?	y
1	1	1	1	0	0 1 0 0 1	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

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- Goal: Given n, k, find feasible testing designs of minimum size.

?	?	?	?	?	?	?	?	y
1	1	1 0 0 1 1	1	0	0	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

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- **X** is *feasible* if we can recover any \mathcal{K} from **y**, $|\mathcal{K}| \leq k$.
- *Goal*: Given *n*, *k*, find feasible testing designs of minimum size.
 - Explicit constructions, efficient decoding rules

Lower bound

?	?	?	?	?	?	?	?	y
1	1 0 1 0	1	1	0	0	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

 Feasible testing design ⇒ ∃ injective function from set of possible defective sets to the set of possible outputs

Lower bound

?	?	?	?	?	?	?	?	y
1	1	1	1	0	0 1 0 0 1	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

• Feasible testing design $\Longrightarrow \exists$ injective function from set of possible defective sets to the set of possible outputs

$$2^T \ge \sum_{i=0}^k \binom{n}{i}$$

Lower bound

?	?	?	?	?	?	?	?	y
1	1	1 0 0 1 1	1	0	0	0	0	1
0	0	0	0	1	1	1	1	1
1	1	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	1	1
0	0	0	0	1	0	0	0	1

 Feasible testing design ⇒ ∃ injective function from set of possible defective sets to the set of possible outputs

$$2^T \ge \sum_{i=0}^k \binom{n}{i} \Longrightarrow T \ge \Omega\left(k \log \frac{n}{k}\right)$$

Sequential design of tests

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- Sequential design of tests
- k = 1
 - ► Conduct binary search. Needs at most [log *n*] tests.
- k > 1
 - Repeat above process, removing one defective in each round.
 - ▶ Needs at most $O(k \log n)$ tests.
 - ▶ More sophisticated algorithms achieve $O(k \log \frac{n}{k})$ tests.
- Order-optimal w.r.t lower bound.



Group testing: bounds

	Lower bound	Upper bound
Adaptive	$k \log \left(\frac{n}{k}\right)$	$k \log \left(\frac{n}{k}\right)$

Testing design matrix has to be specified beforehand.

$$\begin{pmatrix} 1 & 0 & 1 & 0 \\ 0 & 1 & 0 & 1 \\ 1 & 1 & 0 & 0 \\ 0 & 0 & 1 & 1 \\ 1 & 0 & 0 & 1 \\ 0 & 1 & 1 & 0 \end{pmatrix}$$

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2-disjunct

```
(1 0 1 0)

(0 1 0 1)

1 1 0 0

(0 0 1 1)

1 0 0 1

(0 1 1 0)

↑ ↑
```

```
(1 0 1 0)

(0 1 0 1)

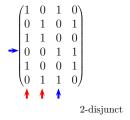
1 1 0 0

(0 0 1 1)

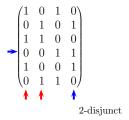
1 0 0 1

(0 1 1 0)

↑ ↑ ↑
```



```
\begin{pmatrix} 1 & 0 & 1 & 0 \\ 0 & 1 & 0 & 1 \\ 1 & 1 & 0 & 0 \\ 0 & 0 & 1 & 1 \\ 1 & 0 & 0 & 1 \\ 0 & 1 & 1 & 0 \end{pmatrix}
```



```
(1 0 1 0)

(0 1 0 1)

1 1 0 0

(0 0 1 1)

1 0 0 1

(0 1 1 0)

1 1 0 0

2-disjunct

Not 3-disjunct
```

Not 3-disjunct

- *t-disjunct matrix*: Union of any *t* columns does not contain any other single column.
- With at most k defectives,

Feasible testing design matrix
$$\begin{cases} \implies (k-1)\text{-disjunct} \\ \iff k\text{-disjunct} \end{cases}$$

$$\begin{pmatrix} 1 & 0 & 1 & 0 \\ 0 & 1 & 0 & 1 \\ 1 & 1 & 0 & 0 \\ 0 & 0 & 1 & 1 \\ 1 & 0 & 0 & 1 \\ 0 & 1 & 1 & 0 \end{pmatrix}$$

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$$\begin{cases} \implies (k-1)\text{-disjunct} \\ \longleftarrow k\text{-disjunct} \end{cases}$$

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 Simple decoding algorithm: if all tests involving an item o/p positive, mark defective.

Non-adaptive testing: bounds

• Lower bound: $\Omega(k^2 \log_k n)$ tests; connection to k-cover families [D'yachkov & Rykov'82, Furedi'96]

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- Explicit construction: O (k² min{log_k² n, log n}) tests; based on a concatenated code construction [Kautz & Singleton'64, Porat & Rotschild'08]

Group testing: bounds

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Adaptive	$k \log \left(\frac{n}{k}\right)$	$k \log \left(\frac{n}{k}\right)$
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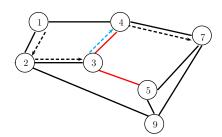
Cascaded Group Testing

with Waqar Mirza and Niranjan Balachandran

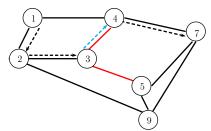
Information Theory Workshop (ITW), Nov. 2024

https://arxiv.org/abs/2405.17917

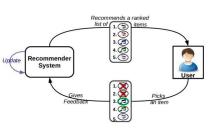
Network tomography



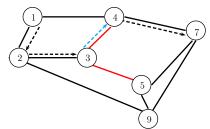
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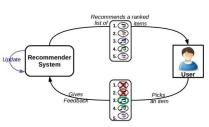
• Recommendation systems [Img. source: "On Recommendation Systems in ε Sequential Context", Frederic Guillou]



Network tomography

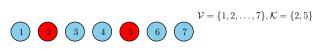


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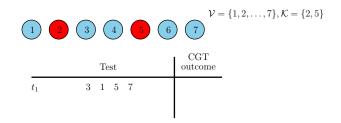


Cascading bandits / OLTR



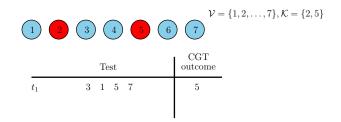


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 - ▶ k ≪ n



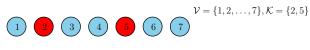
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- Test *t* returns first defective item in the sequence.





			Те	st			CGT outcome
t_1		3	1	5	7		5
$\overline{t_2}$	1	2	3	4	5	6	 2

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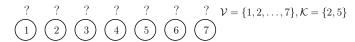
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 - 0 if no defective in test.





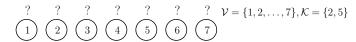
Test	CGT outcome
t_1 3 1 5 7	5
t_2 1 2 3 4 5 6	2
t ₃ 1 3 4 6 7	0
t_4 6 3 4 7	0
t_5 7 5 4 6	5

• Testing design $\mathbf{X} = \{t_1, t_2, ..., t_T\}$, output $\mathbf{y} = (y_1, y_2, ..., y_T)$



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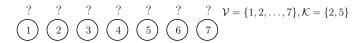
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- *Goal*: Given *n*, *k*, find feasible testing designs of minimum size.





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 - Explicit constructions, efficient decoding rules





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Test	CGT outcome	BGT outcome
t_1 3 1 5 7	5	Yes
t_2 1 2 3 4 5 6	2	Yes
t_3 1 3 4 6 7	0	No
t_4 6 3 4 7	0	No
t ₅ 7 5 4 6	5	Yes



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CGT test provides at least as much information as BGT test.





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- ullet Feasible design under BGT \Longrightarrow Feasible design under CGT



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- CGT test provides at least as much information as BGT test.
- ullet Feasible design under BGT \Longrightarrow Feasible design under CGT
 - Upper bounds for BGT are also upper bounds for CGT
- How much can the additional information help?



Cascaded GT vs Binary GT: bounds

BGT	Lower bound	Upper bound
Adaptive	$k \log \left(\frac{n}{k}\right)$	$k \log \left(\frac{n}{k}\right)$
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Adaptive testing



Sequential design of tests

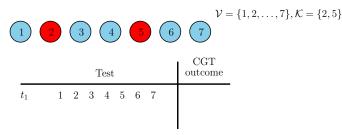
Adaptive testing



- Sequential design of tests
- Initialise $V = \{1, 2, ..., n\}$, $\hat{K} \leftarrow \emptyset$, $i \leftarrow 1$ and run the loop:
 - **1** Run a test with items in $V \setminus \hat{K}$ in an arbitrary order.
 - 2 If the test returns 0, terminate and return $\hat{\mathcal{K}}$.
 - 3 If the test returns v, then update $\hat{\mathcal{K}} \leftarrow \hat{\mathcal{K}} \cup \{v\}$.
 - **4** Update $i \leftarrow i + 1$. If i > k, terminate and return $\hat{\mathcal{K}}$.

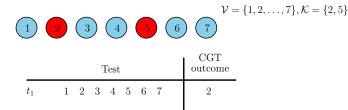


Adaptive testing



- Sequential design of tests
- Initialise $V = \{1, 2, ..., n\}$, $\hat{K} \leftarrow \emptyset$, $i \leftarrow 1$ and run the loop:
 - 1 Run a test with items in $V \setminus \hat{K}$ in an arbitrary order.
 - 2 If the test returns 0, terminate and return $\hat{\mathcal{K}}$.
 - **3** If the test returns v, then update $\hat{\mathcal{K}} \leftarrow \hat{\mathcal{K}} \cup \{v\}$.
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$\overline{t_1}$	1	2	3	4	5	6	7	2
t_2	1	3	4	5	6	7		5

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- Needs at most k tests,



$$V = \{1, 2, ..., 7\}, \mathcal{K} = \{2, 5\}$$

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 - **4** Update $i \leftarrow i + 1$. If i > k, terminate and return $\hat{\mathcal{K}}$.
- Needs at most k tests, optimal in the worst-case.

Cascaded group testing: bounds

BGT	Lower bound	Upper bound
Adaptive	$k \log \left(\frac{n}{k}\right)$	$k \log \left(\frac{n}{k}\right)$
Non-adaptive	$k^2 \log_k n$	$k^2 \min\{\log_k^2 n, \log n\}$
CGT	Lower bound	Upper bound
Adaptive	k	k
Non-adaptive		$k^2 \min\{\log_k^2 n, \log n\}$

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- Optimal for k = 1, 2. BGT would need $\Omega(\log n)$ tests.
- What about larger k?

 $\mathcal{V} = \{1, 2, \dots, 7\}, k = |\mathcal{K}| = 3$

	Test
$\overline{t_1}$	3 1 5 7
t_2	1 2 3 4 5 6
t_3	1 3 4 6 7
t_4	6 3 4 7
t_5	7 5 4 6



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Test	CGT outcome
t_1 3 1 5 7	
t_2 1 2 3 4 5 6	
t_3 1 3 4 6 7	
t_4 6 3 4 7	
t ₅ 7 5 4 6	

- Testing design **X** is *feasible* if we can recover \mathcal{K} from **y**.
- Distinct outputs for each $K_1 \neq K_2$, s.t. $|K_1|, |K_2| \leq k$.

Test	CGT outcome	$\mathcal{K}_1 = \{1, 2, 3\}$
t_1 3 1 5 7	3	
t_2 1 2 3 4 5 6	1	
t_3 1 3 4 6 7	1	
t_4 6 3 4 7	3	
t_5 7 5 4 6	0	

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Test	CGT outcome	$\mathcal{K}_1 = \{1, 2, 3\}$ $\mathcal{K}_2 = \{1, 3\}$
t_1 3 1 5 7	3	
t_2 1 2 3 4 5 6	1	
t_3 1 3 4 6 7	1	
t_4 6 3 4 7	3	
t _z 7 5 4 6	0	

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t_4 6 3 4 7	3	
t= 7 5 4 6	0	

- Testing design X is *feasible* if we can recover K from y.
- Distinct outputs for each $K_1 \neq K_2$, s.t. $|K_1|, |K_2| \leq k$.
- Analogue of disjunctness property under BGT.

 $\mathcal{V} = \{1, 2, \dots, 7\}, k = |\mathcal{K}| = 3$

	Test
$\overline{t_1}$	3 1 5 7
t_2	1 2 3 4 5 6
t_3	1 3 4 6 7
t_4	6 3 4 7
t_5	7 5 4 6



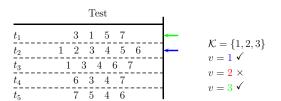
	Test
$\overline{t_1}$	3 1 5 7
t_2	1 2 3 4 5 6
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$$\kappa$$
, and for every $v\in\mathcal{K}$,

 $\mathcal{K} = \{1, 2, 3\}$ v = 1 v = 2 v = 3

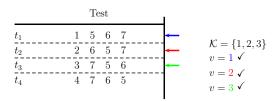




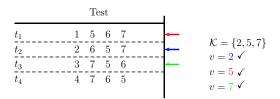


		Те	est		
$\overline{t_1}$	1	5	6	7	
t_2	2	6	5	7	 _
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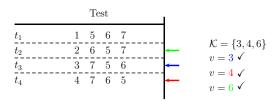














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	Test	CGT outcome	
$\overline{t_1}$	1 5 6 7	6	10 (0.4.0)
t_2	2 6 5 7	6	$\mathcal{K} = \{3, 4, 6\}$
t_3	3 7 5 6	3	
t_4	4 7 6 5	4	

- Feasibility condition: $\forall \ \mathcal{K} \subset V$ with $|\mathcal{K}| = k$, and for every $v \in \mathcal{K}$, \exists test $t \in \mathbf{X}$ where v appears before every other item in \mathcal{K} .
- Reconstruction: $\hat{\mathcal{K}} = \{y_i : i \in [T], y_i \neq 0\}$



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- Lower bound: Any feasible design has at least $\lfloor \frac{k+1}{2} \rfloor \lceil \frac{k+1}{2} \rceil$ tests. $Erd \tilde{o}s$ -Szekeres theorem gives $\lfloor \log_2 \log_2 (n-1) \rfloor$ lower bound.

Cascaded group testing: bounds

Non-adaptive

BGT		Lower bound		Upper bound	
Adaptive		$k \log \left(\frac{n}{k}\right)$		$k \log \left(\frac{n}{k}\right)$	
Non-adaptive		$k^2 \log_k n$	$k^2 \min\{\log_k^2 n, \log n\}$		
CGT	CGT Lower bound			Upper bound	
Adaptive	Adaptive k			k	

 $\max\{k^2, \log\log n\} \mid k^2 \min\{\log_k^2 n, \log n\}$

a = 3

1 2 3 4 5 6 7 8 9

Use feasible design X₁ for a items to create feasible design X₂ for a² items.



- Use feasible design X₁ for a items to create feasible design X₂ for a² items.
- Partition a^2 items into disjoint sets A_1, A_2, \dots, A_a of size a each.

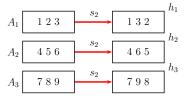
$$a = 3, s_1 = (2, 3, 1), s_2 = (1, 3, 2)$$

1 2 3 4 5 6 7 8 9

• Given permutations s_1, s_2 on a items, permutation $s_3 = s_1 \circ s_2$ on a^2 items is given by:

$$a = 3, s_1 = (2, 3, 1), s_2 = (1, 3, 2)$$





- Given permutations s_1, s_2 on a items, permutation $s_3 = s_1 \circ s_2$ on a^2 items is given by:
 - For each i, arrange items of A_i according to s_2 . Call result h_i .

$$a = 3, s_1 = (2, 3, 1), s_2 = (1, 3, 2)$$

$$1 \quad 2 \quad 3 \quad 4 \quad 5 \quad 6 \quad 7 \quad 8 \quad 9$$

$$A_1 \quad 1 \quad 2 \quad 3 \quad s_2 \quad 1 \quad 3 \quad 2$$

$$A_2 \quad 4 \quad 5 \quad 5 \quad 4 \quad 6 \quad 5 \quad 7 \quad 9 \quad 8 \quad 1 \quad 3 \quad 2$$

$$A_3 \quad 7 \quad 8 \quad 9 \quad 5 \quad 7 \quad 9 \quad 8 \quad 1 \quad 3 \quad 2$$

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$$A_{4} \quad 5 \quad 6 \quad 7 \quad 8 \quad 9$$

$$A_{5} \quad 6 \quad 7 \quad 8 \quad 9$$

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$$A_{6} \quad 7 \quad 8 \quad 9$$

$$A_{7} \quad 7 \quad 8 \quad 9 \quad 1 \quad 3 \quad 2$$

$$A_{8} \quad 7 \quad 8 \quad 9 \quad 1 \quad 3 \quad 2$$

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$$A_{9} \quad 7 \quad 9 \quad 8 \quad 1 \quad 3 \quad 2$$

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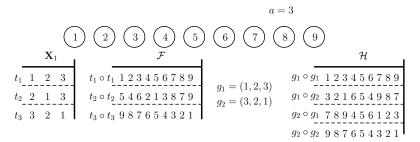


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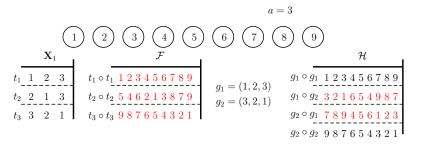
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- Take $g_1 = (1, 2, ..., a)$ and $g_2 = (a, a 1, ..., 1)$.



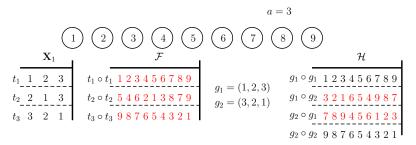


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- Take $g_1 = (1, 2, ..., a)$ and $g_2 = (a, a 1, ..., 1)$. Consider $\mathcal{H} := \{g_i \circ g_j : i, j \in [2]\}$.



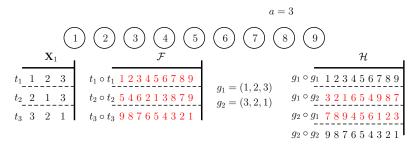


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- Take $g_1 = (1, 2, ..., a)$ and $g_2 = (a, a 1, ..., 1)$. Consider $\mathcal{H} := \{g_i \circ g_j : i, j \in [2]\}$.
- Finally, design for a^2 items given by $\mathbf{X}_2 := \mathcal{F} \cup \mathcal{H}$



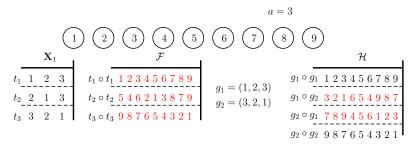
X₂ is a feasible design;



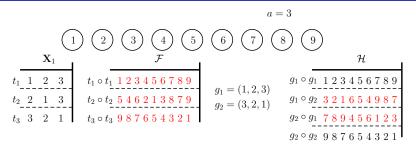


• X_2 is a feasible design; $|X_2| \le |X_1| + 4$

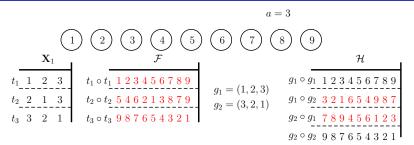




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- Recursive design for n items,

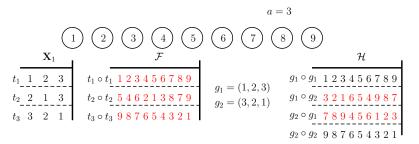


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- Recursive design for n items, with at most $O(\log \log n)$ tests.



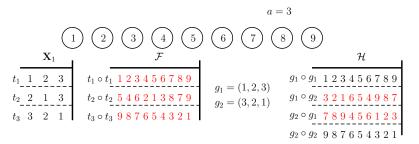
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- Recursive design for n items, with at most $O(\log \log n)$ tests.
- Idea generalizes to any constant k, with at most $O((\log \log n)^{c_k})$ tests, where $c_k = 2^{(k-2)} 1$.
- Can be much smaller than BGT which needs $\Omega(k^2 \log_k n)$ tests.

Cascaded group testing: bounds for k = O(1)

BGT	Lower bound	Upper bound
Adaptive	k log n	k log n
Non-adaptive	$k^2 \log n$	$k^2 \log n$

CGT	Lower bound	Upper bound
Adaptive	k	k
Non-adaptive	$\max\{k^2, \log\log n\}$	$\min\{(\log\log n)^{c_k}, k^2\log n\}$

New variant of group testing

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- Derived bounds under adaptive and non adaptive testing

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- Further directions:

- New variant of group testing
- Derived bounds under adaptive and non adaptive testing
- Further directions:
 - General achievable strategies for any k
 - Close gap between upper and lower bounds
 - Noisy and constrained testing

Thanks

https://sites.google.com/site/nikhilkaram/

```
1 0 1 0
0 1 0 1
1 1 0 0
0 0 1 1
1 0 0 1
0 1 1 0
1 1 0
2-disjunct
```

Not 3-disjunct

- *t-disjunct matrix*: Union of any *t* columns does not contain any other single column.
- With at most k defectives,

Feasible testing design matrix
$$\begin{cases} \implies (k-1)\text{-disjunct} \\ \iff k\text{-disjunct} \end{cases}$$

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$$\begin{pmatrix} 1 & 0 & 0 & 1 \\ 1 & 0 & 1 & 0 \\ 0 & 1 & 1 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 1 \end{pmatrix}$$
 Say $k = 4$, \mathbf{X} not $(k - 1)$ -disjunct
$$\mathbf{X}_1 \preceq \bigvee_{i \in [2:4]} \mathbf{X}_i \Longrightarrow \bigvee_{i \in [2:4]} \mathbf{X}_i = \bigvee_{i \in [1:4]} \mathbf{X}_i$$
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$$\begin{pmatrix} 1 & 0 & 0 & 1 \\ 1 & 0 & 1 & 0 \\ 0 & 1 & 1 & 0 \\ 0 & 1 & 0 & 0 \\ 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 1 \end{pmatrix} \quad \text{Say } k = 4, \mathbf{X} \text{ not } (k-1)\text{-disjunct}$$

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$$O/p \text{ for } \mathcal{K} = \{2, 3, 4\} \text{ same as for } \mathcal{K} = \{1, 2, 3, 4\}$$

$$\Longrightarrow \mathbf{X} \text{ not feasible for } k = 4.$$

$$2\text{-disjunct}$$

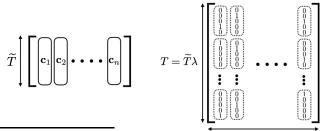
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Non-adaptive testing: bounds

- Lower bound: $\Omega(k^2 \log_k n)$ tests; connection to k-cover families [D'yachkov & Rykov'82, Furedi'96]
- Random construction: $O\left(k^2 \log \frac{n}{k}\right)$ tests; choose each entry i.i.d. $\sim Ber(1/(k+1))$.
- Explicit construction: O (k² min{log_k² n, log n}) tests; based on a concatenated code construction [Kautz & Singleton'64, Porat & Rotschild'08]



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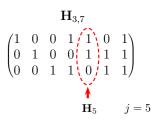
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 - All columns are distinct non-zero binary vectors.
 - Item j defective \Rightarrow output $\mathbf{y} = \bigvee_{i \in \mathcal{K}} \mathbf{H}_i = \mathbf{H}_j$

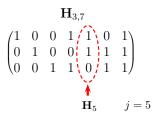
$$\mathbf{H}_{3,7}$$

$$\begin{pmatrix} 1 & 0 & 0 & 1 & 1 & 0 & 1 \\ 0 & 1 & 0 & 0 & 1 & 1 & 1 \\ 0 & 0 & 1 & 1 & 0 & 1 & 1 \end{pmatrix}$$

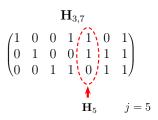
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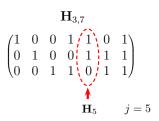
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Extensions and variants

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- Defectives prior: combinatorial, i.i.d., bursty
- Noise model: symmetric, Z channel, dilution, erasure
- Testing model: threshold, quantitative, concomitant, tropical, graph-constrained

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